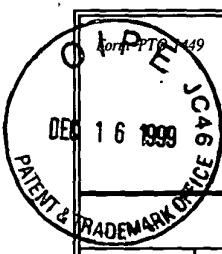


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO MI22-1171	SERIAL NO		
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		FILING DATE		GROUP			
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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GJM	AJ	3,933,530	01/20/76	Mueller et al.			
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AL						No
	AM						
	AN						
	AO						
	AP						
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GJM	AR	Improvement of $SiO_2/Si$ Interface Properties by Fluorine Implantation, K. Ohya, Y. Nishioka, Y. Ohji, and					
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		pp. 574-577.					
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EXAMINER S. Akram			DATE CONSIDERED 10/23/00				
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	AI					
	AJ					
	AK					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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